

## UPCOMING WEB SEMINAR

**August 17, 2006**

### **A PERSONAL INVITATION TO JOIN US AT AUTOTESTCON 2006**

Join us at Autotestcon 2006 in Anaheim, California from September 18 - 21 at the Disneyland Hotel Convention Center. Bring a copy of this e-mail to our booth (#1101) for a free gift!

#### **"House of Blues" Teradyne Celebration**

Be our guest for a special celebration of tradition and technology.

Date: Tuesday, September 19 from 7:30 PM to 11: PM

Location: "House of Blues" in Disneyland

#### **New Product Demonstrations**

Teradyne will demonstrate two new Core System Instrumentation (CSI) products, including the Di-Series of high-performance digital test instruments and the Ai-760 high-density analog test instrument. On display for the first time in a public venue will be our Spectrum Commercial Aircraft Test System. Please visit our booth for more detailed information and technical demonstrations.

#### **Daily Raffle Prizes**

Tuesday at 2:00 PM

Wednesday at 11:30 AM and 3:00 PM

Thursday at 11:30 AM

Prize: Military Dress Vermont Teddy Bear(tm)

Drop your business card at either registration desk to enter!

#### **Technical Workshop**

"iStudio(tm): Advanced Facility for TPS Development and Debug for Complex Instruments" by Teresa Lopes. Monday, Sept 18, 10:00 AM to Noon - The Avalon C Room

iStudio is a graphical test development and debugging environment for use with Teradyne instrumentation. iStudio provides an advanced set of tools to enter, input, edit, debug, export, and organize test. This workshop will focus on the use of iStudio, provide an overview of iStudio's architecture, and focus on creating a UUT-centric digital test. Several debugging and deployment scenarios will also be explored. Examples will demonstrate how an iStudio developed test can be deployed using several development environments, including LabWindows/CVI, Visual Studio.Net and LabVIEW. The demonstration includes debugging a test running in iStudio, debugging a deployed iStudio-generated test, debugging an externally generated test, and debugging a test executed on a remote computer.

#### **IEEE Paper Presentations**

1) "Asynchronous Interaction Between UUTs and LRU-Centric Digital Test Instruments" by Michael McGoldrick. Wednesday, Sept 20, 8:00 AM - 11:45 PM, Track C, the Avalon Rooms A/B

This paper provides a range of problems and solutions involving the asynchronous interaction between UUTs and digital test instruments during LRU and SRU test. It demonstrates how agile handling of asynchronous activity can result in higher test quality, simpler programming, and less debugging. Examples provided are compared to the applications workarounds generally required by older and more synchronous apparatus.

2) "A Net-Centric Instrument Driver Approach for Multi-Computer System Architectures" by Teresa Lopes. Wednesday, Sept 20, 8:00 AM - 11:45 PM, Track C, the Avalon Rooms A/B  
There is a growing interest among system architects to employ multiple computers. Typically, one central computer runs the test executive and user interface, and other computers control the multiple instrument chassis. This architecture produces complexity regarding the location of the instrument driver and associated development and debugging tools. This paper describes the software architecture for a complex digital test instrument that allows the driver and associated tools to be co-located with the test executive even though the instrument is actually resident remotely and controlled by another computer.

3) "Integrating A Graphical Instrument Development Environment With An Existing Applications Development Environment And Test Executive" by Yonet Eracar  
Wednesday, Sept 20, 1:30 PM - 5:15 PM, Track C, the Avalon Rooms A/B  
This paper describes a graphical instrument-specific development environment that generates standard-language test code or a test data file that can be consumed by virtually any Applications Development Environment (ADE). Examples demonstrate where code is appropriate, where pure data is appropriate, and how it is used by the various available commercial ADE and Executive environments.

For general conference and registration information, go to  
<http://www.autotestcon.com/2006/2006.htm>

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